## Notice of References Cited Application/Control No. 10/579,483 Examiner BENYAM KETEMA Applicant(s)/Patent Under Reexamination EICH ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0128191	07-2003	Strasser et al.	345/173
*	В	US-6,282,464	08-2001	Obradovich, Michael L.	701/1
*	С	US-5,841,428	11-1998	Jaeger et al.	345/184
*	D	US-6,636,197	10-2003	Goldenberg et al.	345/156
*	Е	US-5,508,703	04-1996	Okamura et al.	341/176
*	F	US-5,559,301	09-1996	Bryan et al.	84/653
*	G	US-6,842,098	01-2005	Van Zeeland, Anthony J.	335/205
*	Н	US-5,572,573	11-1996	Sylvan et al.	455/556.2
*	1	US-5,717,423	02-1998	Parker, David N.	345/108
*	J	US-6,441,806	08-2002	Jaeger, Denny	345/172
	K	US-			
	Ĺ	US-			7
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 03/088164	10-2003	WIPO	Wells, William	G06F 3/033
	0					
	Р					
-	Q					
	R					
	s					
	I					

## NON-PATENT DOCUMENTS

* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U			
	V			
	w			
	x			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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